Chinastandards.org

CCS H83

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 21447-2018

Specification for cadmium selenide monocrystal of CdSe-N-T01 used for infrared solid state laser

CdSe-N-T01型红个固体激光器用硒化镉单晶材料规范

(English Translation)

Issued by: Ministry of Industry and Information Technology

Preview: page 1 of 3 shown, 14 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21447-2018

Table of Contents

[Preview only]
1 Scope
2 Normative References
2.1 Terms
3 Terms and Definitions
4 Overview
4.1 General requirements
5 Technical Requirements
6 Calibration conditions
6.1 Environmental conditions
6.2 Measurement standards and other equipment
7 Calibration items and calibration methods
7.1 Calibration Items
7.2 Calibration method
8 Expression of calibration results
9 Recalibration interval

1 Foreword

SJ 21447-2018 was issued by Ministry of Industry and Information Technology on 18 January 2018.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 14 pages in English translation.

2 Scope Preview

SJ 21447-2018 is filed under Chinese Standard Classification H83, in the field of metallurgy.

This catalogue holds 1,191 other SJ standards without an ICS number.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

Preview: page 2 of 3 shown, 14 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21447-2018

3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 14 pages (approximate)

Chinese original: about 20,279 characters

4 Related standards

Standards on related subjects:

GB/T 25074-2017 - Solar-grade polycrystalline silicon

SJ/T 11488-2015 - Test method for measuring resistivity, hall coefficient and determining hall mobility in semi-insulating GaAs single crystals

YS/T 13-2015 - High pure germanium tetrachloride

SJ 21444-2018 - Specification for gallium oxide monocrystalline wafers of beta -Ga203-N

SJ 21443-2018 - GaN-N type low resistance gallium nitride single wafer specification

SJ 21442-2018 - GaN-based SI type semi-insulating gallium nitride single wafer specification

5 Classification and status

Chinese Standard Classification (CCS): H 83

Prefix SJ: mandatory standard.

Preview: page 3 of 3 shown, 14 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21447-2018